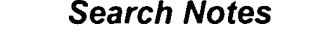


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/615,554	DOBISZ ET AL.
	Examiner Tianjie Chen	Art Unit 2652

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner